



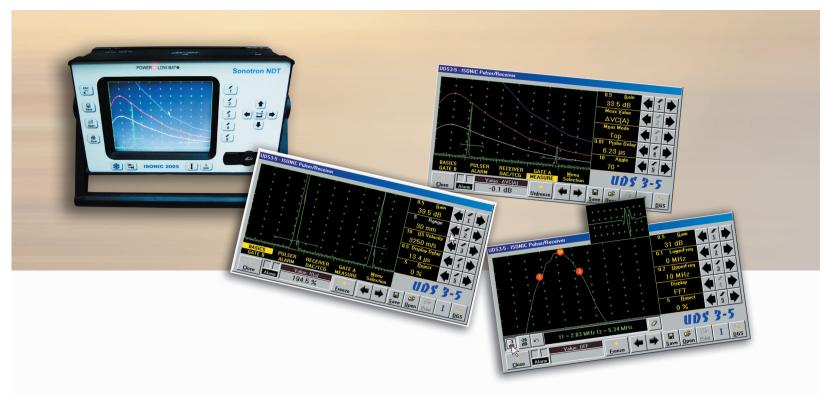
- Large Bright High Resolution Color Touch Screen
- Built-In Encoder Interface
- USB, LAN, VGA outputs
- Huge Data Storage Capability
- Longitudinal, Shear, Guided, and Surface Waves
- A-Scan, B-Scan, CB-Scan, and TOFD

- Corrosion Profiling and Flaw Imaging
- Up To 20m Length of One Line Scan Record
- Playback A-Scans for recorded Images
- Enhanced Signal Evaluation Live and Frozen A-Scans
- Defect Sizing and Pattern Analysis
- Compliance with ASME and RBIM Procedures



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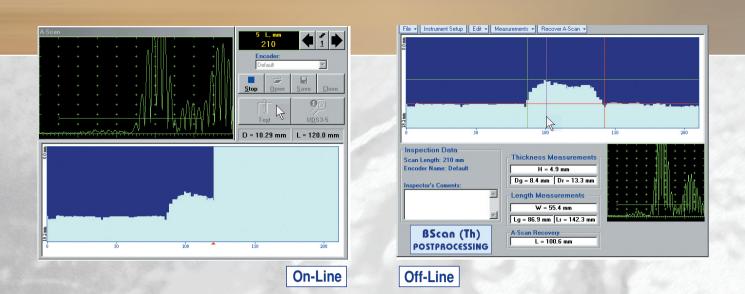


ISONIC 2005 uniquely combines functionality and mobility of high performance portable digital ultrasonic flaw detector with recording, imaging, and data processing capabilities of smart computerized inspection system

Conventional pulse echo and through transmission A-Scan-based inspection

- 640X480 pixels A-Scan display with physical dimensions 130 x 92 mm (5.12" x 3.62") of working area is largest one for the plurality
 of portable ultrasonic flaw detectors
- Combined adjustable spike wave / square wave pulser equipped with variety of probe impedance matching coils provides optimal ultrasound penetration for various materials characterized either by high or low grain, sound attenuation, and the like
- High frequency probe may not be destroyed occasionally upon connecting to instrument's firing output even if duration of square wave initial pulse is improperly long thanks to probe damage prevention circuit automatically limiting energy transmitted to probe's crystal
- 46 dB dynamic range 20 dB/µs maximum slope multiple curve DAC/TCG may be created using up to 40 data points to correct distance

 amplitude variations of ultrasonic signals
- Both theoretical and experimental DAC may be activated either through keing in dB/mm (dB/") factor or through sequential recording echo amplitudes from variously located equal reflectors
- DAC/TCG may be applied to rectified A-Scans (positive, negative, and full wave) and to RF A-Scans as well
- Built-in DGS library for standard probes is unlimitedly expandable
- Thanks to extended dynamic range signals significantly exceeding A-Scan height (up to 199.9%) may be evaluated without drop of instrument Gain
- Whilst A-Scan is frozen managing of Gain and Gates settings is still allowed and provides bringing signals to necessary evaluation level and performing required evaluation
- Dual Ultrasound Velocity Measurement Mode extremely simplifies resolving of sound path distances for dissimilar materials adjacent to each other whereas different values of ultrasound velocity are valid for corresponding signals appearing on the same A-Scan
- RF display mode combined with frequency domain signal analysis enhances capabilities of the instrument for materials characterization, bond inspection, testing of dissimilar materials, defect pattern analysis, and probes evaluation
- Optional data logger organizes and manages database files capable to store up to 254745 thickness readings each and organized as 2D matrix. In database every thickness reading is accompanied with corresponding raw data A-Scan and instrument setup. Automatic creating of MS Excel® thickness spreadsheet meets requirements of various Risk Based Inspection and Maintenance (RBIM) procedures
- And more... see the technical data page



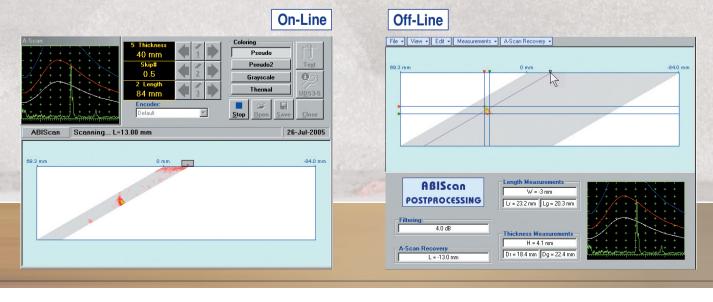
Thickness Profile imaging and recording is performed through continuous capturing of thickness readings along probe trace:

- Both time-based (real time clock) and true-to-location (built-in incremental encoder interface) modes of data recording are supported
- Complete sequence of A-Scans is recorded along with thickness profile
- Off-line evaluation of thickness profile record is featured with:
 - Sizing of thickness damages at any location along stored image: remaining thickness, thickness loss, and length of damage
 - Play-back and evaluation of A-Scans obtained during scanning
 - Reconstruction of thickness profile image for various Gain and/or Gate setings
 - Automatic conversion of thickness profile B-Scan data into MS Excel[®] thickness spreadsheet meeting requirements of various Risk Based Inspection and Maintenance (RBIM) procedures
 - Typical Application: Corrosion detection and characterization

B-Scan cross-sectional imaging and recording of defects for longitudinal and shear wave inspection is performed through continuous measuring of echo amplitudes and reflectors coordinates along probe trace:

- Both time-based (real time clock) and true-to-location (built-in incremental encoder interface) modes of data recording are supported
- Complete sequence of A-Scans is recorded along with B-Scan defects images
- Off-line evaluation of B-Scan record is featured with:
 - Sizing of defects at any location along stored image coordinates and projection dimensions
 - Play-back and evaluation of A-Scans obtained during scanning
 - Defects outlining and echo-dynamic pattern analysis
 - Reconstruction of B-Scan defects images for various Gain and/or Reject settings
 - DAC / DGS B-Scan normalization

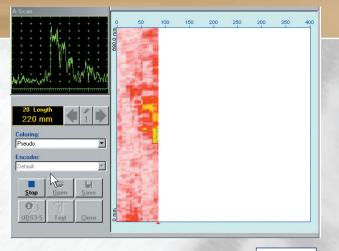
Typical Applications: Pulse echo inspection of welds, composites, metals, plastics, and the like

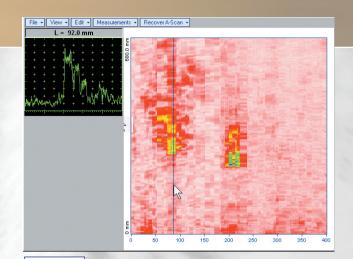


ISONIC 2005

Routine and Secondary Inspection Defects Recording and Characterization Comprehensive Off-Line Analysis Outstanding Documenting Features







On-Line

Off-Line

CB-Scan horizontal plane-view imaging and recording of defects for shear, surface, and guided wave inspection is performed through continuous measuring of echo amplitudes and reflectors coordinates along probe trace:

Both time-based (real time clock) and true-to-location (built-in incremental encoder interface) modes of data recording are supported

On-Line

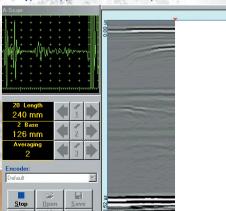
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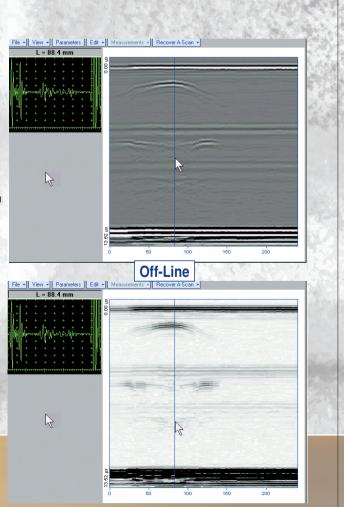
- Complete sequence of A-Scans is recorded along with CB-Scan defects images
- Off-line evaluation of CB-Scan record is featured with:
 - Sizing of defects at any location along stored image coordinates and projection dimesions
 - Play-back and evaluation of A-Scans obtained during scanning
 - Defects outlining and echo-dynamic pattern analysis
 - Reconstruction of CB-Scan defects images for various Gain and/or Reject settings
 - DAC/DGS CB-Scan normalization

Typical Applications: Long range pulse echo and CHIME inspection of annular plates and pipes for pitting, stress corrosion, etc; weld inspection, surface wave inspection

TOFD Inspection – RF B-Scan and D-Scan Imaging:

- Both time-based (real time clock) and true-to-location (built-in incremental encoder interface) modes of data recording are supported
- Averaging A-Scans whilst recording as per operator's selection
- Complete sequence of RF A-Scans is recorded along with TOFD map
 - Off-line evaluation of TOFD Map is featured with:
 - Improvement of near to surface resolution through removal of lateral wave and/or back echo record
 - Linearization and straightening
 - Play-back and analysis of A-Scans obtained during scanning
 - Increasing contrast of TOFD images through varying Gain setting and/or rectification
 - Defects pattern analysis and sizing
 - Zoom of TOFD Map and A-Scans
 - Typical Applications: weld inspection; CHIME inspection





ISONIC 2005 – Technical Data

Pulse Type: Initial Transition: Pulse Amplitude:

Pulse Duration:

Energy (Spike Pulse): Modes: Damping: Internal Matching Coil – Probe Impedance Matching: PRF: Optional Sync Output / Input: Gain: Advanced Low Noise Design: Frequency Band: Ultrasound Velocity: Range: Display Delay: Probe Angle: Probe Delay: Display Modes: Reject: DAC / TCG:

DGS: Gates: Gate Start and Width:

Gate Threshold: Measuring Functions – Digital Display Readout:

Freeze Mode (A-Scans and Spectrum Graphs):

Encoder Interface: Imaging Modes: Encoding: Length of one record: Method of Record: Region of Interest:

Off-Line Image Analysis: Data Reporting:

Data Storage Capacity:

Data Logger:

On-Board Computer: RAM: Flash Memory - Quasi HDD: Outputs: Screen:

Controls: Compatibility with the external devices:

Operating System: Power: Housing: Dimensions:

Weight:

Positive Spike Pulse / Positive Square Wave Pulse ≤5 ns (10-90%) Spike pulse - smoothly tunable (18 levels) 50...400 V into 50 Ω at 4 levels of Excitation Energy Square wave pulse - smoothly tunable (18 levels) 50...400 V into 50 Ω Spike pulse - 10...70 ns for 50 Ω load depending on Energy and Damping setup Square wave pulse - 65...600 ns controllable in 5 ns step 4 discrete energy values / 40 μJ (min) to 250 μJ (max) Single / Dual 17 discrete resistances values / 25 Ω min to 1000 Ω max

16 discrete inductivity values / 2 μ H min to 78 μ H max 0 Hz - optionally; 0...5000 Hz controllable in 1 Hz resolution Max +5V, $\tau \le 5$ ns, t ≥ 100 ns, Load Impedance $\ge 50 \Omega$ 0...120 dB controllable in 0.5 dB resolution 93 μ V peak to peak input referred to 80 dB gain / 35 MHz bandwidth 0.35...35 MHz Wide Band / 34 Sub Bands 300...20000 m/s (11.81...787.4 "/ms) controllable in 1 m/s (0.1 "/ms) resolution 0.5...3000 μ s - controllable in 0.01 μ s resolution 0...90° controllable in 10.01 μ s resolution 0...70 μ s controllable in 0.01 μ s resolution 0...70 μ s controllable in 0.01 μ s resolution - expandable RF, Rectified (Full Wave / Negative or Positive Half Wave), Signal's Spectrum (FFT) 0...99 % of screen height controllable in 1% resolution Theoretical - through keying in dB/mm (dB/") factor Experimental - through sequential recording echo amplitudes from variously located Experimental - through sequential recording echo amplitudes from variously located equal reflectors 46 dB Dynamic Range, Slope \leq 20 dB/µs, Capacity \leq 40 points Available for the Rectified and RF Display Standard Library for 18 probes / unlimitedly expandable 2 Independent Gates / unlimitedly expandable Controllable over the whole variety of A-Scan Display Delay and A-Scan Range in 0.1 mm /// 0.001" resolution 5...95% of the A-Scan height controllable in 1% resolution 27 automatic functions / expandable; Dual Ultrasound Velocity Measurement Mode for Multi-Layer Structures; Curved Surface/Thickness/Skip correction for angle beam probes; Ultrasound Velocity and Probe Delay Auto-Calibration for all types of probes All measurements functions, managing Gates and Gain settings are available for frozen signals Built-in interface for incremental mechanical encoder Thickness Profile B-Scan, Cross-sectional B-Scan, Plane View CB-Scan, TOFD Time-based or True-to-location (incremental encoder) 50...20000 mm (2"...800"), automatic scrolling Complete raw data recording Controllable over entire Display Delay, Probe Delay, Range, US Velocity and other appropriate instrument settings instrument settings Recovery of A-Scan sequences, Defects sizing, outlining, pattern recognition Direct printout of Calibration Dumps, A-Scans, Spectrum Graphs, thickness profile B-Scans, cross-sectional B-Scans, plane view CB-Scans, TOFD maps At least 10000 sets including calibration dumps accompanied with A-Scans and/or Spectrum Graphs; At least 10000 sets including calibration dumps accompanied with thickness profile B-Scans or cross-sectional B-Scans or plane view CB-Scans or TOFD maps Optional - organizes and manages data base files capable to store up to 254745 records each; every record includes thickness reading accompanied with corresponding raw data A-Scan and instrument setup; records are organized into 2D matrix in database file AMD LX 800 - 500MHz 512 Megabytes 512 Megabytes 4 Gigabytes LAN, USB X 2, PS 2, SVGA 6.5" High Color Resolution (32 bit) SVGA 640x480 pixels 133x98 mm (5.24" x 3.86") Sun-readable LCD; Maximal A-Scan Size (working area) - 130x92 mm (5.12" x 3.62") Front Panel Sealed Keyboard, Front Panel Sealed Mouse, Touch Screen PS 2 Keyboard and Mouse, USB Keyboard and Mouse, USB Flash Memory card, Printer through USB or LAN, PC USB or LAN, SVGA External Monitor Windows[™]XP Embedded Mains - 100...240 VAC, 40...70 Hz, auto-switch; Battery 12V 8AH up to 6 hours continuous operation IP 53 rugged aluminum case with carrying handle 265×156×101 mm (10.43"×6.14"×3.98") - without battery 265×156×139 mm (10.43"×6.14"×5.47") - with battery 2.650 kg (5.83 lbs) - without battery 3.580 kg (7.88 lbs) - with battery